Inventor: Hui-Chuan Hung

Serial No.: To Be Assigned Filed: Herewith
For: In-Situ Electron Beam Induced Current Detection

Attorney Doc. No.: 67,200-1152

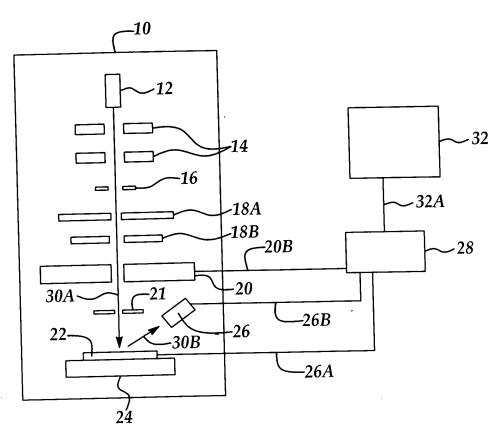
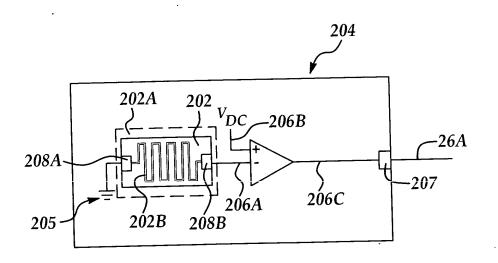


Figure 1



<u>Figure 2A</u>

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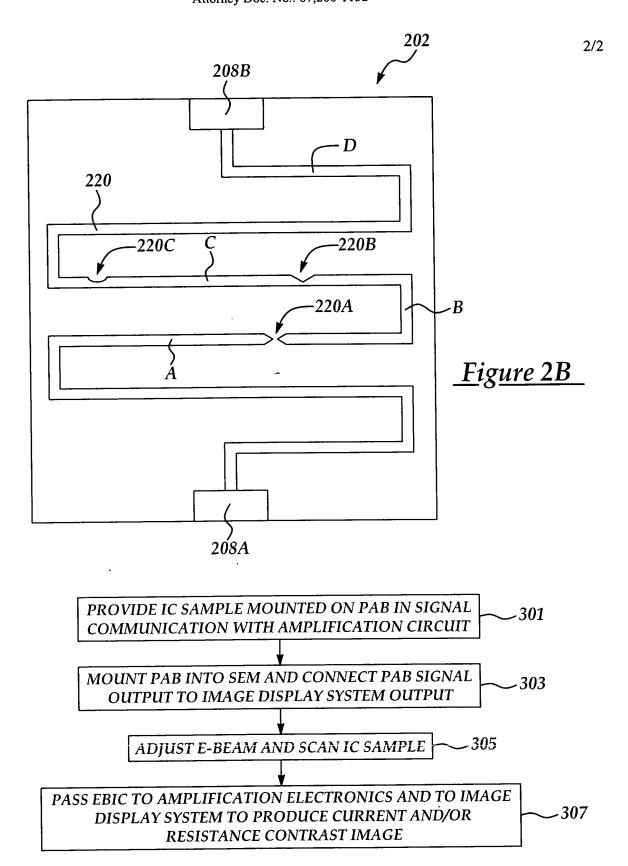


Figure 3